



# Defect Reduction TWG - ITRS

## IMEC April 10-12, 2000

AGENDA	UPDATE
• Yield Model Re-Evaluation	2000
• SoC Yield Model-Interfaces	2001
• Mini-Line Yield Management	2001
– Yield Goals for Pilot Line	
• Edge Die	2001
– Yielding to Edge/Metrology/Yield Limiter Generated at Edge	

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### AGENDA

### UPDATE

- Measuring Dishing/Warping/  
Flatness 2001
- Combining Defect Reduction/  
Metrology/Automatic Process  
Control - How to get efficiencies? 2001
- FOUP Particle Control/  
Maintenance 2001

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## IMEC April 10-12, 2000

### AGENDA

### UPDATE

- 10-15 Year Subjects
  - Making 100% Yield
  - Zero-Fault Control
  - Early Warning Defect Detection (In-situ)
  - Address inspection of vertical structures
  - Project new defects from new materials and sub-0.1 um structures
  - and more